XRD

MILE HIGH RESOLUTION XRD **EVERGREEN D**

Chair: **K. Evans-Lutterodt**, Brookhaven National Laboratory, Upton, NY

3:50 D-73 **High Resolution X-ray Diffraction of III-Nitride Wide Bandgap Semiconductors**
Q. Sun, B. Leung, J. Han, *Yale University, New Haven, CT*

4:10 D-17 **High-Resolution Reciprocal Space Mapping of InGaAs/GaAs Structures: From Pseudomorphic to Fully Relaxed State**
A. Ulyanenkov, *Bruker AXS GmbH, Karlsruhe, Germany*
F. Rinaldi, S. Menzel, *Ulm University, Ulm, Germany*
A. Benediktovich, A. Zhilik, I. Feranchuk, *Belarussian State University, Minsk, Belarus*
K. Saito, *Bruker AXS K.K., Yokohama, Japan*

4:30 D-36 **In-Plane Diffraction Analysis for Twist/Twin Structure of Non-Polar A-Plane GaN**
Y.-i. Jang, K.-h. Park, K.-h. Bang, *LG Advanced Research Institute, Seoul, Korea*

4:50 D-1 **Effect of Substrate Temperature on the Structural, Optical and Electrical Properties of Silver Indium Selenide Films Prepared by Laser Ablation**
D. Pathak, R.K. Bedi, *Guru Nanak Dev University, Amritsar, India*
D. Kaur, *Indian Institute of Technology, Roorkee, India*

THURSDAY PM

XRF

X-RAY IMAGING **EVERGREEN B**

Chair: **G.J. Havrilla**, Los Alamos National Laboratory, Los Alamos, NM

2:00 F-22 ***Invited*—X-ray Absorption Imaging for Analysis of Gas Discharges in Energy-Efficient Lighting**
J.J. Curry, *NIST, Gaithersburg, MD*

2:30 F-3 **STXM Imaging of Organic Coatings on Grains in Primitive Interplanetary Dust: Implications for Formation of Pre-Biotic Organic Matter and Grain Sticking in the Early Solar System**
G.J. Flynn, *SUNY-Plattsburgh, Plattsburgh, NY*
S. Wirick, C. Jacobsen, *SUNY- Stony Brook, Stony Brook, NY*
L.P. Keller, *NASA Johnson Space Center, Houston, TX*
S.A. Sandford, *NASA Ames Research Center, Moffett Field, CA*

2:50 F-37 **Macroscopic X-ray Fluorescence Capability for Large-Scale Elemental Mapping**
H.M. Volz, G.J. Havrilla, R.M. Aikin, Jr., V.M. Montoya, A.N. Duffield, *Los Alamos National Laboratory, Los Alamos, NM*

3:10 F-29 **Overlay of Laboratory-Based 3D X-ray Imaging Systems**
B.M. Patterson, G.J. Havrilla, B. Jackson, *Los Alamos National Laboratory, Los Alamos, NM*

3:30 **Break**

4:00 F-26 ***Invited*—X-ray Chemical Imaging in Scanning and Projection Modes in the Laboratory**
K. Tsuji, K. Nakano, *Osaka City University, Osaka, Japan*